

Notice of References Cited	Application/Control No. 09/735,256	Applicant(s)/Patent Under Reexamination BLOUIN ET AL.	
	Examiner Freda A. Nelson	Art Unit 3639	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,529,790	03-2003	Magee et al.	700/121
*	B	US-6,202,039	03-2001	Finger, Eugene P.	702/189
	C	US-			
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Way et al., "An Overview of manufacturing Yield and reliability Modeling for Semiconductor Products", August 1999, Proceedings of the IEEE, VOL. 87, NO. 8.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.